


<p style="text-align: center;">Search Notes</p> 	<p>Application/Control No.</p> <p>10552494</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>ST-DENIS, YVES</p>
	<p>Examiner</p> <p>Jaisle, Cecilia M</p>	<p>Art Unit</p> <p>1624</p>

SEARCHED			
Class	Subclass	Date	Examiner
514	222.5, 252.04, 255.05, 269	10/19/2007	Cecilia Jaisle
544	8, 238, 279	10/19/2007	Cecilia Jaisle
514	222.5, 252.04, 255.05, 269	5/18/2008	C. Jaisle
544	8, 238, 279	5/18/2008	C. Jaisle

SEARCH NOTES		
Search Notes	Date	Examiner
STN and Inventor Names searched by STIC	10/19/2007	Cecilia Jaisle

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
514	222.5, 252.04, 255.05, 269	5/18/2008	C. Jaisle
544	8, 238, 279	5/18/2008	C. Jaisle